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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

2184
#4
1-29-03
JM

In re Application of

Atty. Docket

NORBERT FELBER ET AL.

CH 000024

Serial No. 10/003,673

Group Art Unit: 2184

Filed: NOVEMBER 2, 2001

Ex.:

Title: METHOD FOR TESTING INTEGRATED CIRCUITS

Commissioner for Patents
Washington, D.C. 20231

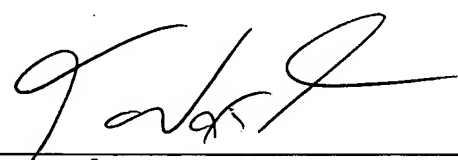
INFORMATION DISCLOSURE STATEMENT UNDER 37 C.F.R. 1.97

Sir:

Enclosed is a copy of a foreign search report issued in
a related application. The documents cited are "A"
(technical background) only.

Respectfully submitted,

By


Aaron Waxler, Reg. 48,027
(914) 333-9608

CERTIFICATE OF MAILING

I hereby certify that this correspondence is being
deposited this date with the United States Postal
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On January 21, 2003
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By Burnett James
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